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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/658,882	CHANG ET AL.	
Examiner	Art Unit	_
Fugene Lee	2815	

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Class	Subclass	Date	Examiner
257	390	6/6/2005	EL
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INTERFERENCE SEARCHED			
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SEARCH NOT (INCLUDING SEARCH		)
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searched EAT, USPAT, JPO, EPO	6/6/2005	EL